

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ASA-481-05

SERIAL NO.

LIST OF DOCUMENTS CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
N. NASEGAWA et alFILING DATE
11/10/98

GROUP

1759

JCS49 U.S. PTO
09/188368

U. S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
JR	AA	5,429,897	07/04/95	Yoshioka et al	430	5	
	AB	5,656,400	08/19/95	Hasegawa et al	430	5	
	AC	5,578,421	11/04/95	Hasegawa et al	430	5	
	AD	5,429,896	07/12/95	Hasegawa et al	430	5	
	AE	4,360,586	11/23/82	Flanders et al	430	5	
	AF	4,890,309	12/26/89	Smith et al	430	5	
	AG	5,328,807	07/12/94	Tanaka et al	430	5	
JR	AH	5,364,716	11/15/94	Nakagawa et al	430	5	
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
JR	AL	62-50811	10/27/87	Japanese Patent Laid-Open				
	AM	4-136854	05/11/92	Japanese patent Laid-Open				
	AN	144453	06/19/91	Japan				
JR	AO	269532	12/02/91	Japan				
	AP							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	JOURNAL OF VACUUM SCIENCE TECHNOLOGY, 16(6), Nov/Dec. 1979, "Spatial period division-A new technique for exposing submicrometer-line width periodic and quasiperiodic patterns", Flanders et al, pp. 1949-1952.
	AS	
	AT	

EXAMINER

DATE CONSIDERED

4-99

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ASA-481-05SERIAL NO.
09/188,368LIST OF DOCUMENTS CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
N. NASEGAWA et alFILING DATE
11/10/98GROUP
1752

U. S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
<i>JA</i>	AA	5,837,405	11/17/98	Tomofuji et al	430	5	
<i>JA</i>	AB	5,660,956	08/26/97	Tomofuji et al	430	5	
<i>JA</i>	AC	5,595,844	01/21/97	Tomofuji et al	430	5	
<i>JA</i>	AD	5,589,305	12/31/96	Tomofuji et al	430	22	
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AR		
	AS		
	AT		

EXAMINER

DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.